

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

1.13.03

**INFORMATION DISCLOSURE
STATEMENT**

Docket Number:
10191/2238

Application Number
To Be Assigned

Filing Date
Herewith

Examiner
To Be Assigned

Art Unit
To Be Assigned

Invention Title
INTERFEROMETRIC MEASURING DEVICE

Inventor(s)
Friedrich PRINZHAUSEN et al.

Assistant Commissioner
for Patents
Washington D.C. 20231
Box Patent Application

1. In accordance with the duty of disclosure under 37 C.F.R. § 1.56 and in conformance with the procedures of 37 C.F.R. §§ 1.97 and 1.98 and M.P.E.P. § 609, attorneys for Applicant hereby bring the following references to the attention of the Examiner. The references are listed on the attached modified PTO Form No. 1449. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that these references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.
2. A copy of each patent, publication or other information listed on the modified PTO form 1449 is enclosed, except as otherwise indicated on the modified PTO form 1449.

Dated: 3/6/02

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3. no.
36,197)

10/070693

INFORMATION DISCLOSURE STATEMENT BY APPLICANTS PTO FORM 1449	Atty. Docket No. 10191/2238	Serial No. To Be Assigned
	Applicant(s) Friedrich PRINZHAUSEN et al.	
	Filing Date Herewith	Group To Be Assigned

U. S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE
	5,321,501*	June 14, 1994	Swanson et al.	356	345	4/29/92

* Copy of reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority).

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
						YES	NO
	197 21 843*	February 11, 1999	DE				
	0 534 795*	March 31, 1993	EP				
	198 08 273*	September 9, 1999	DE				
	41 08 944**	September 24, 1992	DE			(Abstract) X	
	199 48 813** +		DE			(Abstract) X	
	100 15 878.1** +		DE			(Abstract) X	

* Copy of reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority).

** Described in the Specification

+ Copies will be submitted shortly.

OTHER DOCUMENTS

EXAMINER'S INITIALS	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
	P. de Groot, L. Deck, "Surface Profiling by Analysis of White-light Interferograms in the Spatial Frequency Domain" J. Mod. Opt., Vol. 42, No. 2, 389-401, 1995**
	Th. Dresel, G. Häusler, H. Venzke, "Three-dimensional sensing of rough surfaces by coherence radar," Appl. Opt., Vol 31 no. 7, 919-925, 1992**

** Described in the Specification

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	